Photometric Spectrum
TEST REPORT

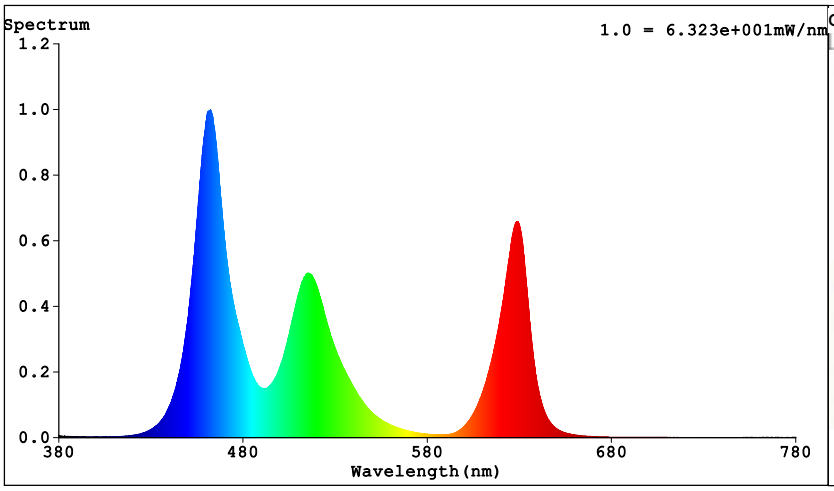
aspectLED

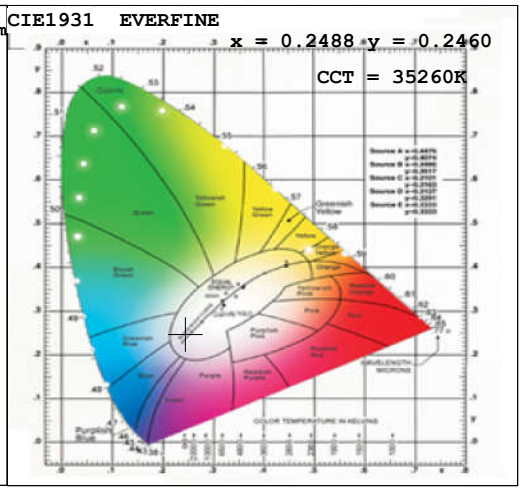
Date	: 2026-05-05	Sam. Status	: First Sample Test
Test by	: E.V.	Instrument	: HaasSuite(EVERFINE)
Specification	: AL-SL-WU-IP68-24-RGB	Remark	: 1M
Sample No.	: 1	Device SN	: HS-2000

Test Condition

Temprature	: 25Deg	RH	: 60.0%
WL Range	: 380nm-780nm	IP	: 52105 (80%)
Test Mode	: Fast Test	T	: 100 ms
Sensitivity	: High		

Spectrum





Colorimetric Parameters

Chromaticity Coordinate: x = 0.2488 y = 0.2460 / u' = 0.1825 v' = 0.4059 (duv=8.36e-04)
CCT= 35260K Prcp WL: Ld=476.4nm Purity=37.0%
Peak WL: Lp=462nm FWHM: =19.7nm Ratio:R=24.0% G=63.4% B=12.6%
Render Index: Ra = 40.2 CRI = 33.2 TM30:Rf=45 Rg=115

EEI: 0.22770 A

R1 =18	R2 =52	R3 =68	R4 =37	R5 =42	R6 =49	R7 =56	
R8 =0	R9 =0	R10=0	R11=20	R12=57	R13=23	R14=76	R15=1

LEVEL:OUT WHITE:OUT

Photometric & Radiometric Parameters

Flux = 767.41 lm Eff. : 54.38 lm/W Fe = 3.5199 W

Electrical parameters

V = 24.00 V I = 0.5881 A P = 14.11 W PF = 1.000 F=0.00 Hz

EVERFINE

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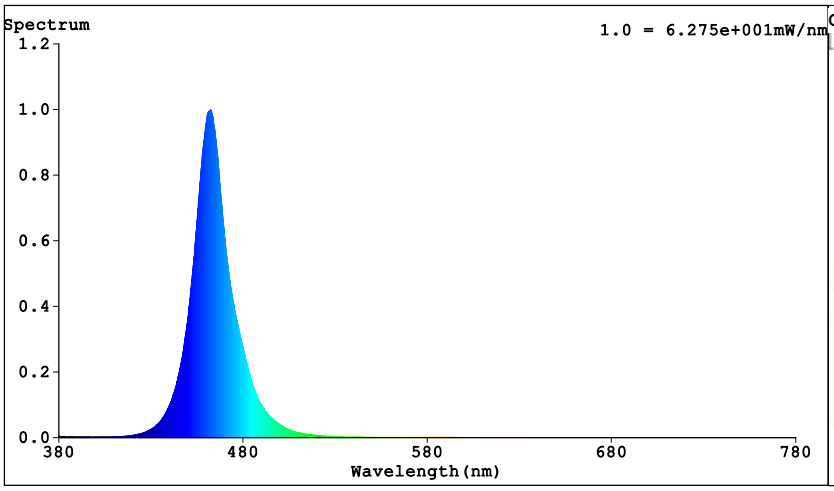
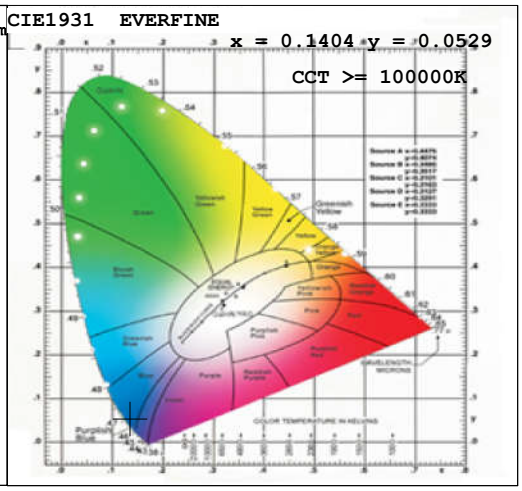
Test by	: E.V.	Instrument	: HaasSuite(EVERFINE)
Specification	: AL-SL-WU-IP68-24-RGB	Remark	: 1M
Sample No.	: 2	Device SN	: HS-2000

Test Condition

Temprature	: 25Deg	RH	: 60.0%
WL Range	: 380nm-780nm	IP	: 53481 (82%)
Test Mode	: Fast Test	T	: 120 ms
Sensitivity	: High		

Spectrum





Colorimetric Parameters

Chromaticity Coordinate: x = 0.1404 y = 0.0529 / u' = 0.1675 v' = 0.1419 (duv=-1.74e-01)
CCT>=100000K Prcp WL: Ld=466.0nm Purity=96.5%
Peak WL: Lp=462nm FWHM: =19.8nm Ratio:R=0.3% G=12.2% B=87.6%
Render Index: Ra = 0.0 CRI = 0.0 TM30:Rf=0 Rg=49

EEI: 0.34802 B

R1 =0	R2 =0	R3 =0	R4 =0	R5 =0	R6 =0	R7 =0	
R8 =0	R9 =0	R10=0	R11=0	R12=0	R13=0	R14=0	R15=0

LEVEL:OUT WHITE:OUT

Photometric & Radiometric Parameters

Flux = 95.300 lm Eff. : 20.65 lm/W Fe = 1.5795 W

Electrical parameters

V = 24.00 V I = 0.1923 A P = 4.615 W PF = 1.000 F=0.00 Hz

EVERFINE

Photometric Spectrum
TEST REPORT

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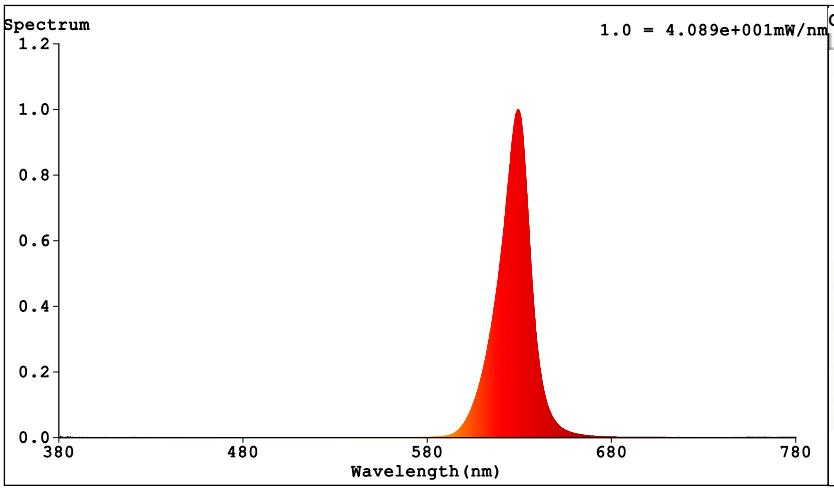
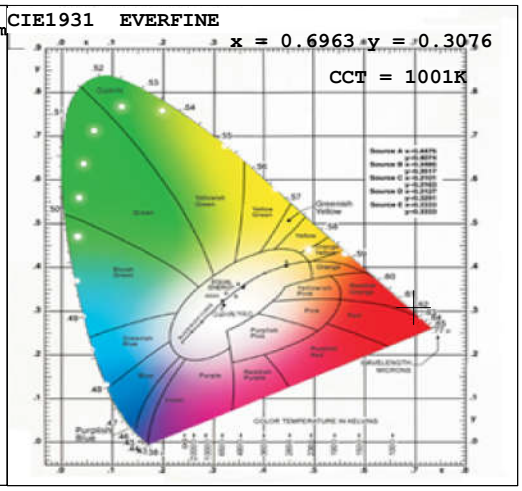
Date	: 2026-05-05	Sam. Status	: First Sample Test
Test by	: E.V.	Instrument	: HaasSuite(EVERFINE)
Specification	: AL-SL-WU-IP68-24-RGB	Remark	: 1M
Sample No.	: 3	Device SN	: HS-2000

Test Condition

Temprature	: 25Deg	RH	: 60.0%
WL Range	: 380nm-780nm	IP	: 53115 (81%)
Test Mode	: Fast Test	T	: 104 ms
Sensitivity	: High		

Spectrum





Colorimetric Parameters

Chromaticity Coordinate: x = 0.6963 y = 0.3076 / u' = 0.5257 v' = 0.5225 (duv=-7.71e-02)
CCT= 1001K Prcp WL: Ld=620.2nm Purity=100.0%
Peak WL: Lp=629nm FWHM: =17.7nm Ratio:R=97.8% G=2.2% B=0.0%
Render Index: Ra = 24.4 CRI = 28.6 TM30:Rf=0 Rg=0

EEI: 0.23552 A

R1 =2	R2 =78	R3 =25	R4 =0	R5 =0	R6 =90	R7 =0	
R8 =0	R9 =0	R10=71	R11=0	R12=79	R13=28	R14=56	R15=0

LEVEL:OUT WHITE:OUT

Photometric & Radiometric Parameters

Flux = 182.58 lm Eff. : 37.20 lm/W Fe = 862.39 mW

Electrical parameters

V = 24.00 V I = 0.2045 A P = 4.908 W PF = 1.000 F=0.00 Hz

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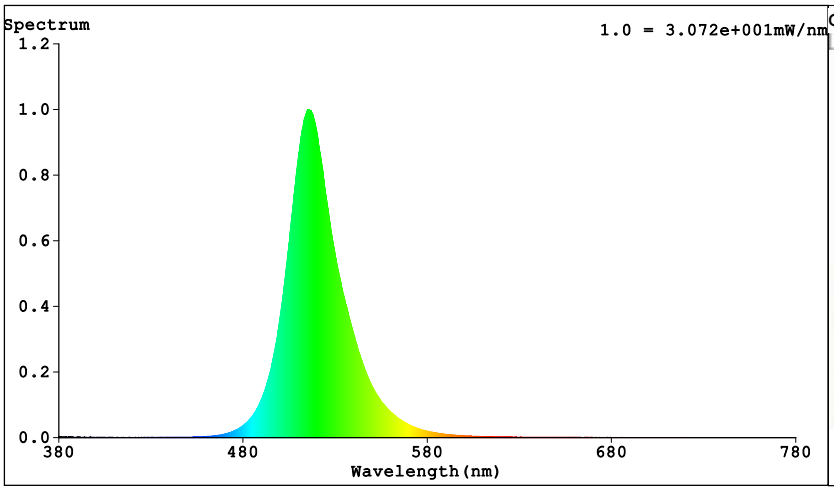
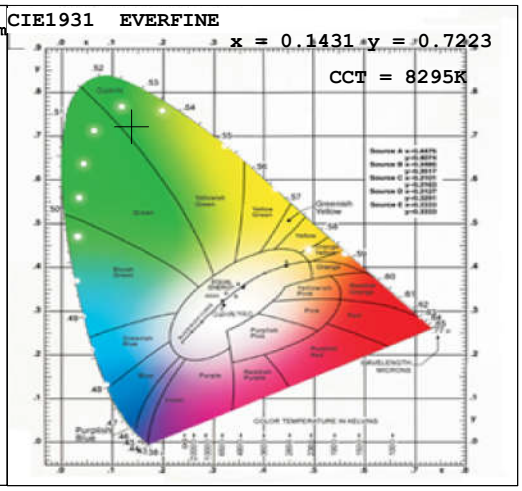
Test by	: E.V.	Instrument	: HaasSuite(EVERFINE)
Specification	: AL-SL-WU-IP68-24-RGB	Remark	: 1M
Sample No.	: 4	Device SN	: HS-2000

Test Condition

Temprature	: 25Deg	RH	: 60.0%
WL Range	: 380nm-780nm	IP	: 53310 (81%)
Test Mode	: Fast Test	T	: 154 ms
Sensitivity	: High		

Spectrum





Colorimetric Parameters

Chromaticity Coordinate: x = 0.1431 y = 0.7223 / u' = 0.0503 v' = 0.5712 (duv=1.65e-01)
CCT= 8295K Prcp WL: Ld=521.9nm Purity=77.8%
Peak WL: Lp=515nm FWHM: =28.8nm Ratio:R=0.2% G=96.8% B=3.0%
Render Index: Ra = 0.0 CRI = 2.4 TM30:Rf=1 Rg=6

EEI: 0.11038 A+

R1 =0	R2 =0	R3 =0	R4 =0	R5 =0	R6 =0	R7 =0	
R8 =0	R9 =0	R10=0	R11=0	R12=0	R13=0	R14=36	R15=0

LEVEL:OUT WHITE:OUT

Photometric & Radiometric Parameters

Flux = 486.74 lm Eff. : 101.92 lm/W Fe = 1.0776 W

Electrical parameters

V = 24.00 V I = 0.1990 A P = 4.776 W PF = 1.000 F=0.00 Hz

EVERFINE